

Application/Control No. 10/511,718	Applicant(s)/Patent under Reexamination LIU ET AL.
Examiner	Art Unit
Rodnev P. Swartz, Ph.D.	1645

				ISSUE	CL	AS	SIF	ICAT	ION					
		ORIGINAL		INTERNATIONAL CLASSIFICATION										
	_ASS			CI	AIMED			NON-						
	3.1	Α	61	K	39	/04				1				
	CROS		A	61	к	49	/00				1			
CLASS	R BLOCK)		01	ı\	49	700				,				
536	23.1	23.7			Α	61	К	39	/00				1	
530	300	350							1				1	
424	9.1	9.2	185.1	190.1					1				1	
424	243.1								1				1	
435	7.1	7.2							1				1	
******* ********				h.D./	Total Claims Allowed: 24									
(Legal In	struments E	ixaminer)	(Date)	(Primary	_	3-200 ner))9	(Date)	O.G. Print Claim(s) 1				O.G. Print Fig.	

Claims renumbered in the same order as presented by applicant									□СРА		☐ T.D.			☐ R.1.47				
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original	Final	Original		Final	Original
1	1			31			61]		91			121		151			181
2	2]		32			62			92			122		152			182
3	3]		33			63			93			123		153			183
4	4]		34			64]		94			124		154			184
5	5]		35			65]		95			125		155			185
6	6]		36			66			96			126		156			186
7	7			37			67]		97			127		157			187
8	8			38			68			98			128		158			188
	9]		39			69]		99			129		159			189
9	10]		40			70]		100			130		160			190
10	11]		41			71			101			131		161			191
11	12]		42			72			102			132		162			192
12	13]		43			73			103			133		163			193
13	14]		44			74]		104			134		164			194
14	15]		45			75]		105			135		165			195
15	16]		46			76]		106			136		166			196
16	17]		47			77			107			137		167			197
17	18]		48			78]		108			138		168			198
18	19			49			79			109			139		169			199
19	20]		50			80]		110			140		170			200
20	21]		51			81]		111			141		171			201
	22]		52			82]		112			142		172			202
21	23]		53			83			113			143		173			203
22	24]		54			84			114			144		174			204
	25]		55			85			115			145		175			205
	26]		56			86]		116			146		176			206
	27]		57			87]		117			147		177			207
23	28]		58			88]		118			148		178			208
	29]		59			89]		119			149		179			209
24	30			60			90			120			150		180			210